Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/909,383	TAGUCHI, AKIRA	
Examiner	Art Unit	
Shin-Hon Chen	2131	

		 			
SEARCHED					
Class	Subclass	Date	Examiner		
726	2,4,19	3/2/2006	S.C.		
726	28-30	3/2/2006	S.C.		
379	88,70	3/2/2006	S.C.		
340	825	3/2/2006	S.C.		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
726	18,19,2,4	3/2/2006	s.c.		
726	28-30	3/2/2006	S.C.		
379	70,88	3/2/2006	S.C.		
340/825		3/2/2006	S.C.		

SEARCH NO (INCLUDING SEARC)
	DATE	EXMR
USPAT, PGPUB, JPO, EPO, DERWENT	3/2/2006	S.C.